## Application/Control No. Applicant(s)/Patent Under Reexamination 09/696,491 PARANCHYCH ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 David Q Nguyen 2681 U.S. PATENT DOCUMENTS Document Number Date Name Classification MM-YYYY Country Code-Number-Kind Code US-Α US-В С US-US-D US-Ε F US-G US-Н US-US-US-J US-Κ L US-М US-**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 98/36508	08-1998		Hamalainen et al	
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